

<b>Notice of References Cited</b>	Application/Control No. 10/574,153		Applicant(s)/Patent Under Reexamination DEYN ET AL.	
	Examiner SUN JAE Y. LOEWE		Art Unit 1626	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-US 11/909,447	03-2006	na	na
*	B	US-7,544,637	06-2009	von Deyn et al.	504/100
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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